

Analysis of Micro-switch Contaminants

A contamination on a micro-switch solder point was analyzed both by the micro FTIR and reflectance methods. Spectrum A is obtained using the normal reflectance method, and spectrum B, using the micro FTIR reflectance method. Spectrum B contains peaks which were not detected in Spectrum A. Using the micro FTIR reflectance method, we can determine that the contaminant is composed of paraffin and silicon compounds.

Measurement conditions

Accumulation: 64
 Resolution: 4 cm^{-1}
 Detector: MCT
 Aperture: 100 μm x 100 μm

